

- 9 (a)** Photoelectrons are emitted with insignificant time lag when electromagnetic radiation of a certain frequency is incident on a metal plate.

State and explain one other observation from the photoelectric effect that provides evidence for the particulate nature of electromagnetic radiation.

[4]

[4]

- (b) Two parallel zinc plates placed a distance d apart are used to investigate the photoelectric effect, as shown in Fig. 9.1. Zinc has a work function of 4.33 eV.

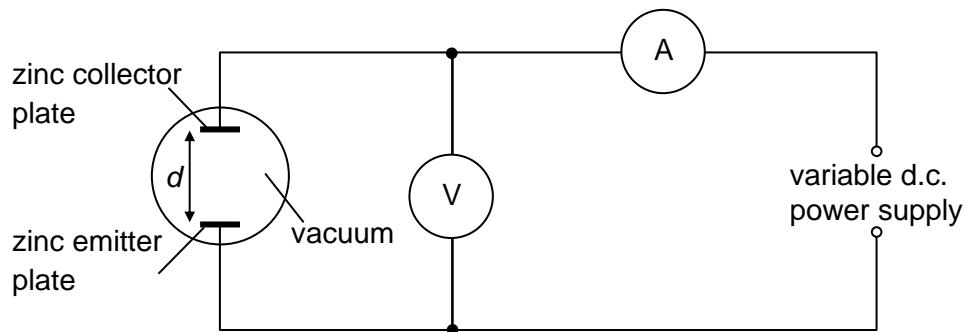


Fig. 9.1

Electromagnetic radiation of wavelength 210 nm is incident on the zinc emitter plate. The potential of the zinc collector plate is varied from -3.0 V to $+3.0\text{ V}$ with respect to the zinc emitter plate.

The variation of the current I with the potential difference V is shown in Fig. 9.2.

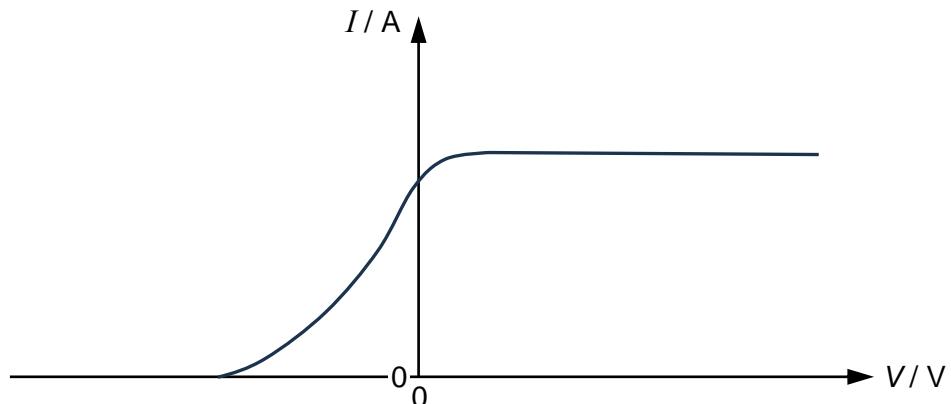


Fig. 9.2

- (i) Calculate the threshold wavelength for the zinc plate.

$$\text{wavelength} = \dots \text{nm} \quad [2]$$

- (ii) Calculate the maximum speed of the emitted photoelectrons.

speed = m s^{-1} [2]

- (iii) Photoelectrons in (b) are emitted perpendicularly to the zinc emitter plate.

Explain why the subsequent motion of the emitted photoelectrons is different when $V = 0 \text{ V}$ and $V = +3.0 \text{ V}$.

[3]

- (iv) On Fig 9.2, draw the variation of I with V if the zinc emitter plate is now illuminated with radiation of a shorter wavelength but the same intensity as in (b).

[2]

- (c) Electrons are accelerated in a vacuum before passing through a graphite film, as shown in Fig. 9.3. The electrons are then incident on a fluorescent screen.

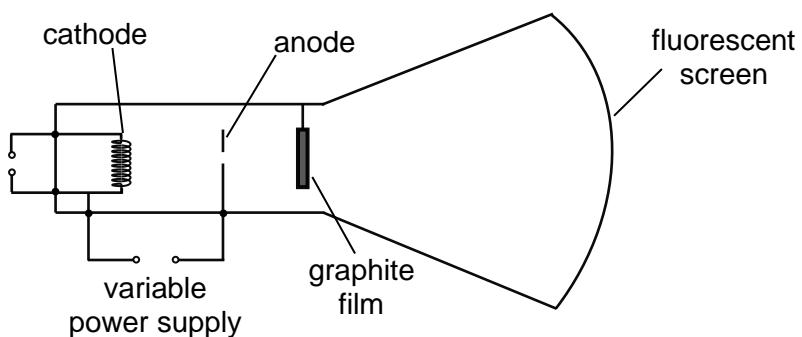


Fig 9.3

Concentric rings of light are observed on the screen.

- (i) Explain how the observation of the concentric rings of light provides evidence for the wave nature of electrons.

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- (ii) The electrons are accelerated from rest through a potential difference of 5.0 kV.

Calculate the de Broglie wavelength of the accelerated electrons.

$$\text{wavelength} = \dots \text{m}$$

[3]

- (iii) Optical and electron microscopy techniques are widely utilised for imaging and analysing microscopic structures.

With reference to **(c)(ii)**, state and explain an advantage of an electron microscope compared to an optical microscope.

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